

ISO 17470:2004-09 (E)

Microbeam analysis - Electron probe microanalysis - Guidelines for qualitative point analysis by wavelength dispersive X-ray spectrometry

Contents		Page
Foreword		iv
Introduction		v
1	Scope	1
2	Normative references	1
3	Terms and definitions	1
4	Abbreviated terms	2
5	Apparatus	2
6	Procedure for identification	2
6.1	General	2
6.2	Setting of analysis conditions	2
6.3	Method for analysing an X-ray spectrum	4
6.4	Detection limit	5
7	Test report	6
Annex A (informative) Example of the test report on qualitative analysis of a stainless steel sample by EPMA		7
Bibliography		10